



FQPF4N20L

200V LOGIC N-Channel MOSFET

General Description

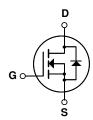
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.s These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, and motor control.

Features

- Low Crss (typical 6.0 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · Low level gate drive requirement allowing direct operation from logic drivers





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQPF4N20L	Units	
V _{DSS}	Drain-Source Voltage		200	V	
I _D	Drain Current - Continuous (T _C = 25°	C)	3.0	Α	
	- Continuous (T _C = 100°C)		1.9	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	12	А	
V_{GSS}	Gate-Source Voltage		± 20	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	52	mJ	
I _{AR}	Avalanche Current	(Note 1)	3.0	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	2.7	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns	
P_{D}	Power Dissipation (T _C = 25°C)		27	W	
	- Derate above 25°C		0.22	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		4.63	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	1	Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced	to 25°C		0.16		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 200 V, V _{GS} = 0 V				1	μΑ
		V _{DS} = 160 V, T _C = 125°C	;			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$		1.0		2.0	V
R _{DS(on)}	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 1.5 \text{ A}$ $V_{GS} = 5 \text{ V}, I_D = 1.5 \text{ A}$			1.10	1.35	
' 'DS(on)	On-Resistance				1.13	1.40	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 25 \text{ V}, I_D = 1.5 \text{ A}$	(Note 4)		2.9		S
Dynam	ic Characteristics Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,			240	310	pF
C _{oss}	Output Capacitance	$v_{DS} = 25 \text{ v}, v_{GS} = 0 \text{ v},$ $f = 1.0 \text{ MHz}$			36	45	pF
C _{rss}	Reverse Transfer Capacitance				6	8	pF
	ng Characteristics						-
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 100 \text{ V, } I_D = 3.8 \text{ A,}$ $R_G = 25 \Omega \qquad \qquad \text{(Note 4, 5)}$			7	25	ns
t _r	Turn-On Rise Time			-	70	150	ns
t _{d(off)}	Turn-Off Delay Time			-	15	40	ns
t _f	Turn-Off Fall Time			-	40	90	ns
Qg	Total Gate Charge	$V_{DS} = 160 \text{ V}, I_D = 3.8 \text{ A},$			4.0	5.2	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 5 V (Note 4, 5)		-	1.0		nC
Q _{gd}	Gate-Drain Charge				1.9		nC
Drain-S	Source Diode Characteristics at Maximum Continuous Drain-Source Dio		S			3.0	A
I _{SM}	Maximum Pulsed Drain-Source Diode F	Pulsed Drain-Source Diode Forward Current				12	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 3.0 \text{ A}$				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 3.8 \text{ A,}$ $dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)			90		ns
Q _{rr}	Reverse Recovery Charge				0.25		uС

- **NOISE:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 8.67mH, I_{AS} = 3.0A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 3.8A, di/dt \leq 300A/µs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300µs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

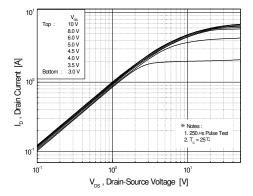


Figure 1. On-Region Characteristics

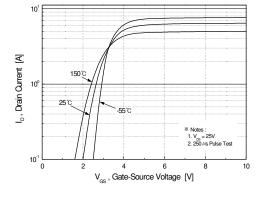


Figure 2. Transfer Characteristics

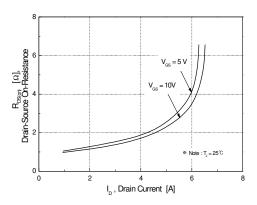


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

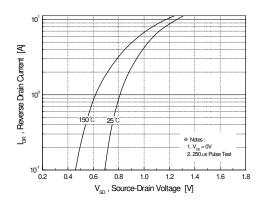


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

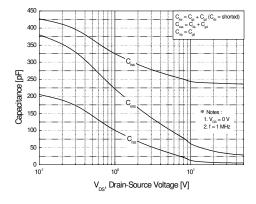


Figure 5. Capacitance Characteristics

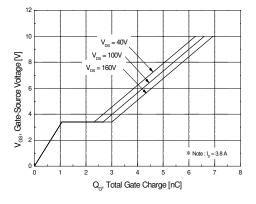
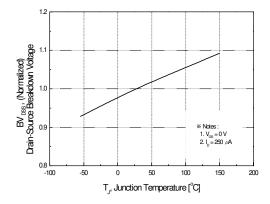


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)



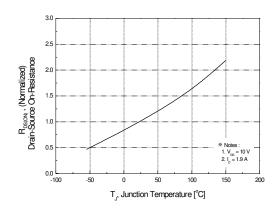
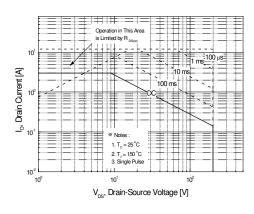


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



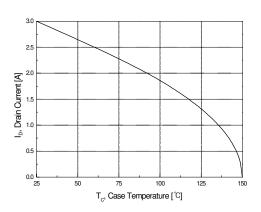


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

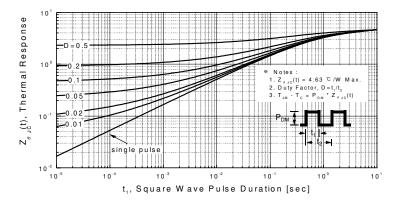
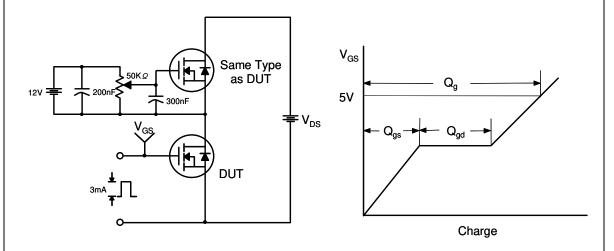


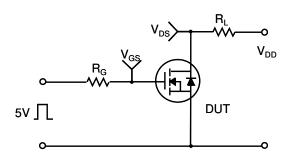
Figure 11. Transient Thermal Response Curve

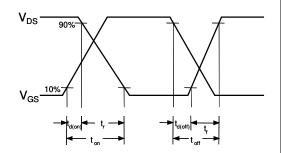
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Gate Charge Test Circuit & Waveform

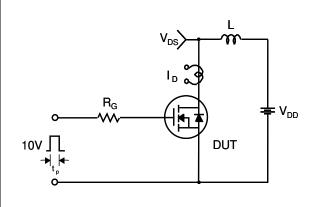


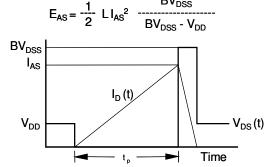
Resistive Switching Test Circuit & Waveforms



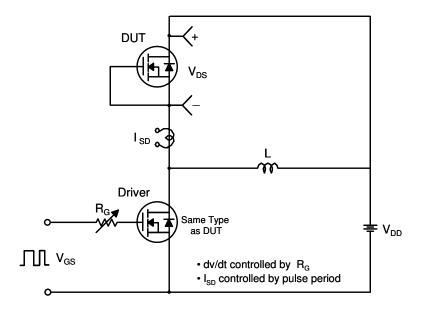


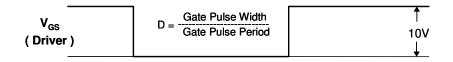
Unclamped Inductive Switching Test Circuit & Waveforms

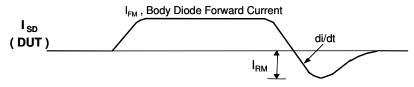




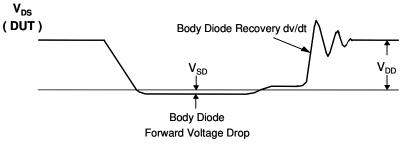
Peak Diode Recovery dv/dt Test Circuit & Waveforms

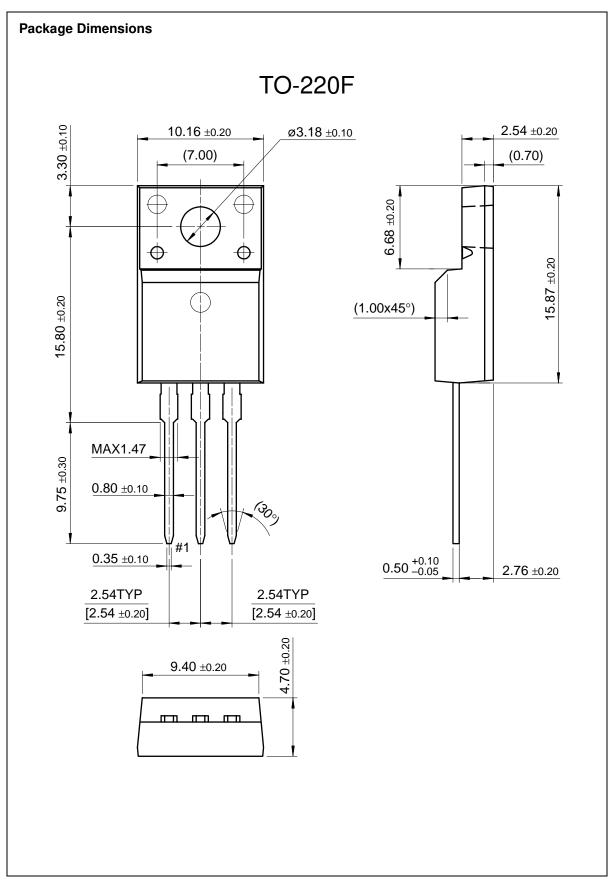






Body Diode Reverse Current





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